

Search Notes**Application/Control No.**

10/786,072

Examiner

Patrick A. Darno

Applicant(s)/Patent under Reexamination

ISHII ET AL.

Art Unit

2163

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|------------|----------|
| 709 | 229 | 11/18/2005 | PAD |
| 709 | 225 | 11/18/2005 | PAD |
| 709 | 218 | 11/18/2005 | PAD |
| 709 | 104 | 11/18/2005 | PAD |
| 455 | 410 | 11/18/2005 | PAD |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |

INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---------------|------------|------|
| EAST | 11/18/2005 | PAD |
| PLUS | 11/18/2005 | PAD |
| IEEE DATABASE | 11/19/2005 | PAD |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |